

Search Notes



Application/Control No.

10/532,226

Examiner

Tran N. Nguyen

Applicant(s)/Patent under Reexamination

JUNG ET AL.

Art Unit

2834

SEARCHED

Class	Subclass	Date	Examiner
310	162 166 168 211	7/4/06	TNN
310	212 216 261	7/5/06	TNN
update	all above	1/18/07	TNN

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR